



High-density Fan-Out Chip on Substrate using M-Series™ and Adaptive Patterning® Technology

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Deca released for IMAPS DPC 2022

Agenda

- Introduction
- Industry Perspective
- Challenges & Solutions
- Design Study
- Conclusion

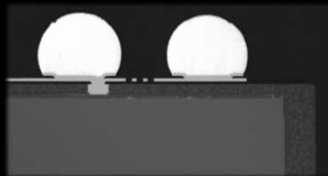
DECA Company introduction

- Deca was born of a passion to transform electronic interconnect with inspiration from SunPower's advanced solar wafer fab
- Our name describes our culture of 10X thinking, inspired by Greek *déka* (δέκα)
- Deca created 10X breakthroughs with M-Series™ & Adaptive Patterning®



SUNPOWER

1.



M-Series*

*Chips first, chips up
fan-out technology*

Gen 1 & Gen 2

2.



Adaptive Patterning*

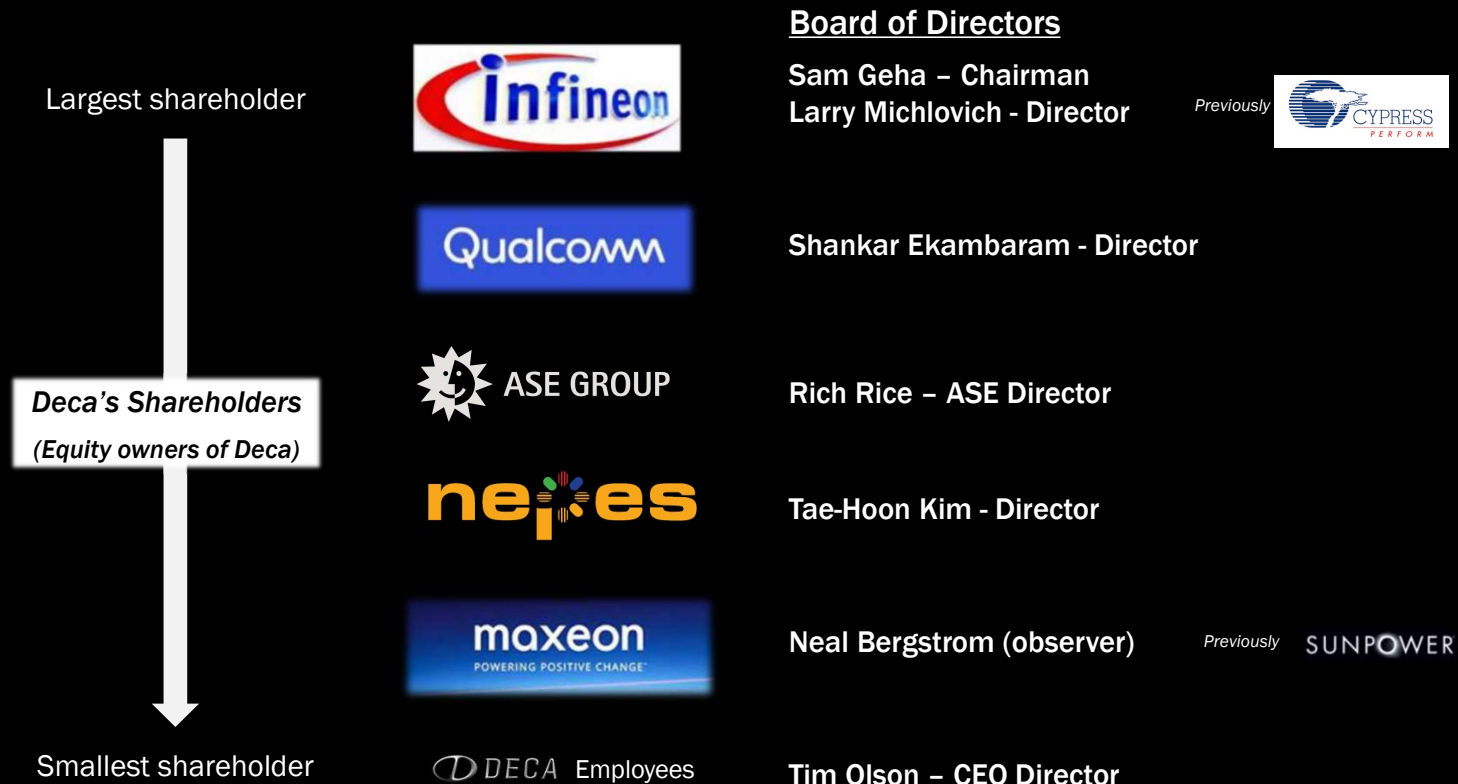
*Real-time optimized design
during manufacturing (every
device on every wafer)*

**Now the industry's #1 fan-out
technology**

**Over 3.5 million devices shipping
per day in Q1'22**

Note: Deca holds > 100 issued and pending patents on M-Series, Adaptive Patterning and related technology

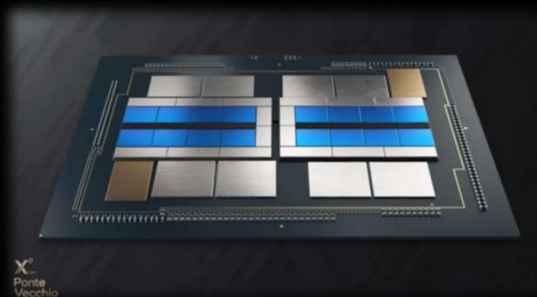
Deca is Owned by Industry Leading Companies



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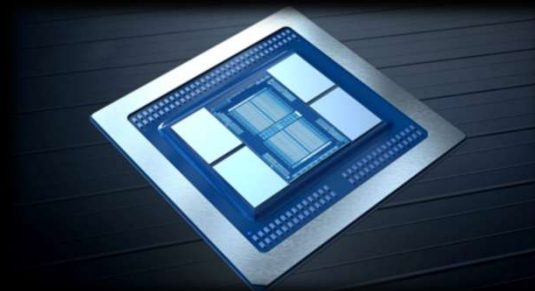
The future is now...



"...Ponte Vecchio Xe-HPC GPU, Over 100 Billion Transistors & 47 XPU Compute Tiles"

<https://wccftech.com/intel-showcases-packaging-prowess-7nm-ponte-vecchio-xe-hpc-gpu-100-billion-transistors/>

Intel's Ponte Vecchio



"AMD Radeon... with Chiplet Design"

<https://www.hardwaretimes.com/amd-radeon-rx-7900-xt-rx-7800-xt-rx-7700-xt-to-leverage-tsmcs-5nm-6nm-node-w-chiplet-design/>

AMD's Radeon

Chiplets are happening

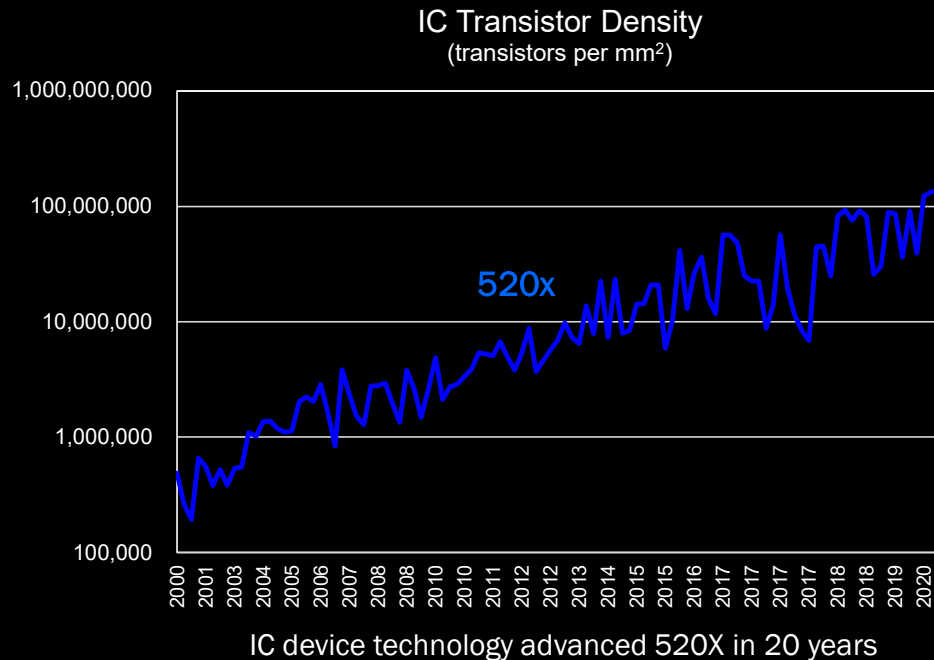
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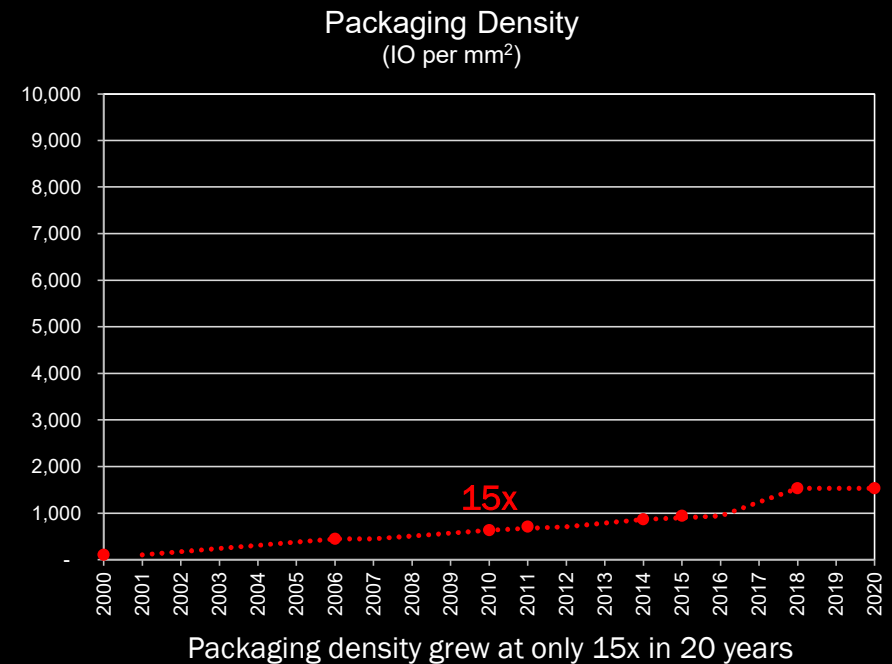


Challenge - Pitch Limitations

Packaging severely lagging semiconductor device technology (15x vs. 500x density increase in past 20 years)



Source: Multiple industry sources compiled at en.wikipedia.org/wiki/Transistor_Count



Sources: 1. Chip scale Review: March-April 2020, IO/mm² derived from die pad pitch data
2. Tech Search Intl, Advanced Packaging Update, Vol 2, 2020

Packaging interface density orders of magnitude behind ICs

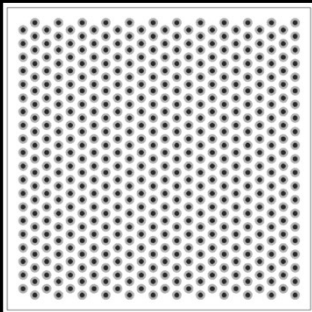


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Challenge - Pitch Limitations

Industry leaders at 40µm to 45µm die pad pitch

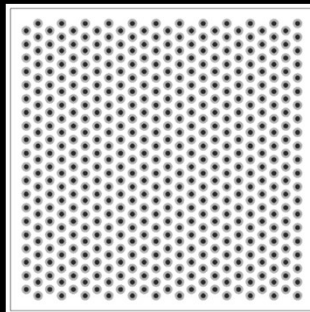
M-Series Gen 1
(Chips First Fan-out)



Die pad pitch: 45 µm
IO per mm²: **492**

Introduced in 2016

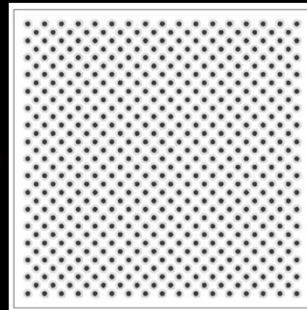
Intel EMIB
(Hybrid chips in substrate)



Die pad pitch: 45 µm*
IO per mm²: **492**

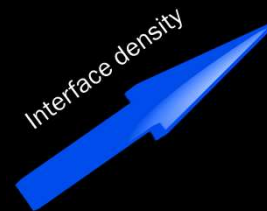
*45µm pitch reference: David Schor, Intel Unveils Foveros Omni And Foveros Direct; Leveraging Hybrid Bonding, WikiChip Fuse, July 26, 2021

TSMC InFO-R
(Chips First Fan-out)

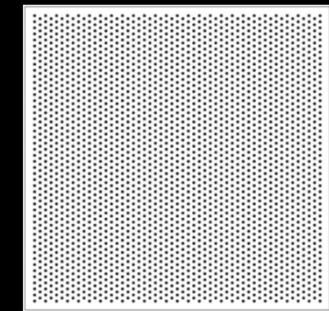


Die pad pitch: 40 µm
IO per mm²: **545**

*40µm pitch reference: Tom Dillinger, SemiWiki.com, Highlights of the TSMC Technology Symposium, 9/7/2020



M-Series Gen 2
(Chips First Fan-out)



Die pad pitch: 20 µm
IO per mm²: **2,518**

Deca's Gen 2 delivers breakthrough 20µm die pad pitch thru Adaptive Patterning

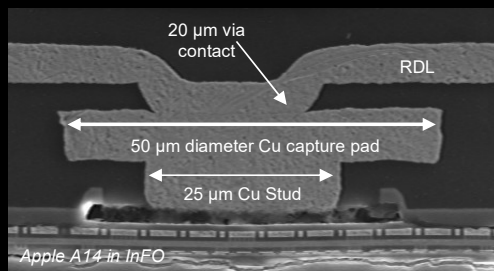
5X interface density increase



Deca released for IMAPS DPC 2022

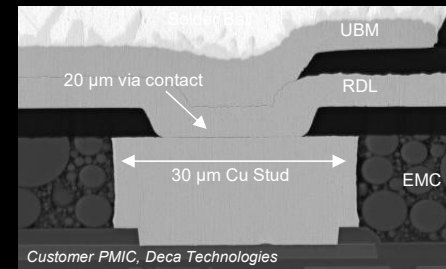
Solution – Eliminating the Capture Pad

Example – TSMC InFO



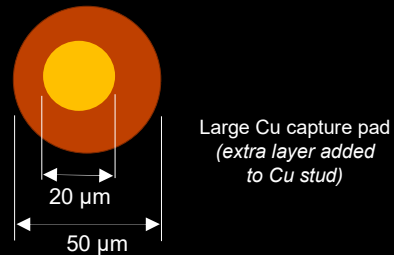
Source: Prismark iPhone 12 Analysis Jan'21

M-Series™ with Adaptive Patterning

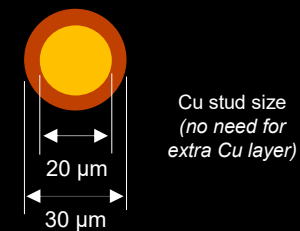


Source: Prismark iPhone 12 Analysis Jan'21

Via connection without Adaptive Patterning

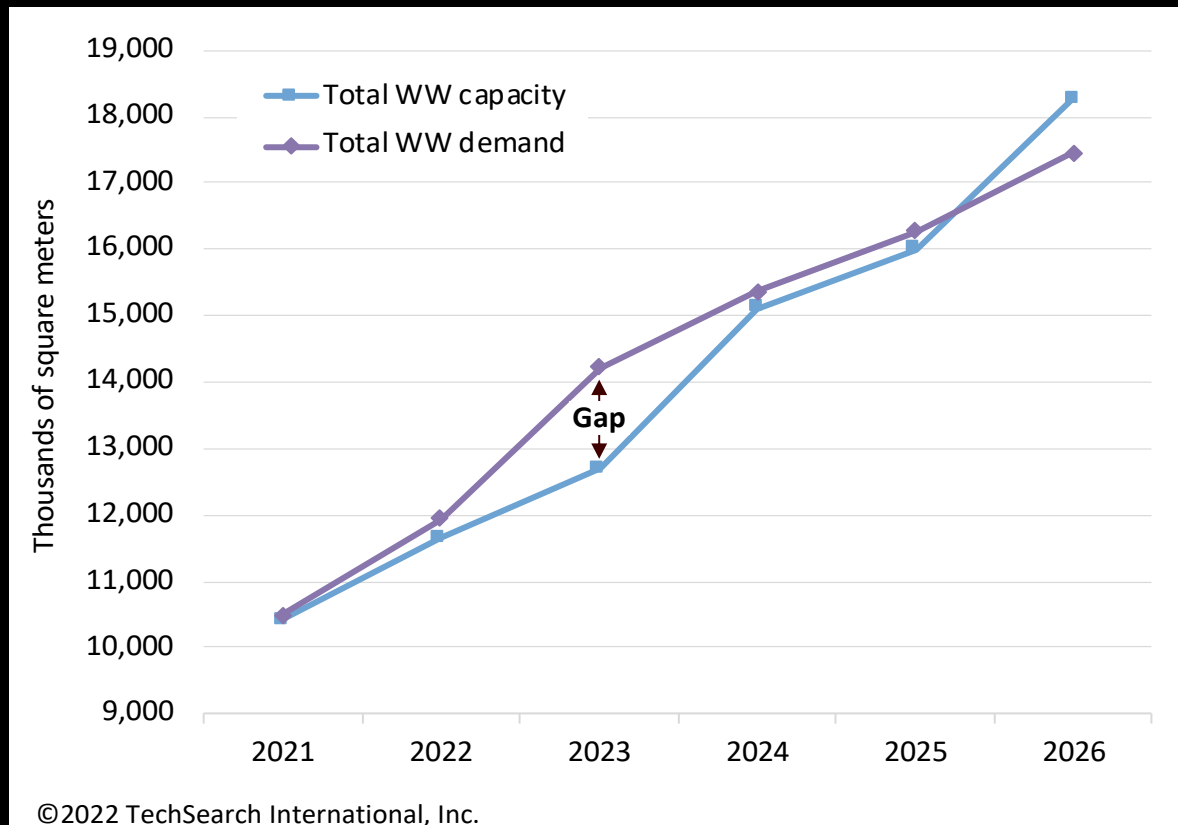


Via connection with Adaptive Patterning



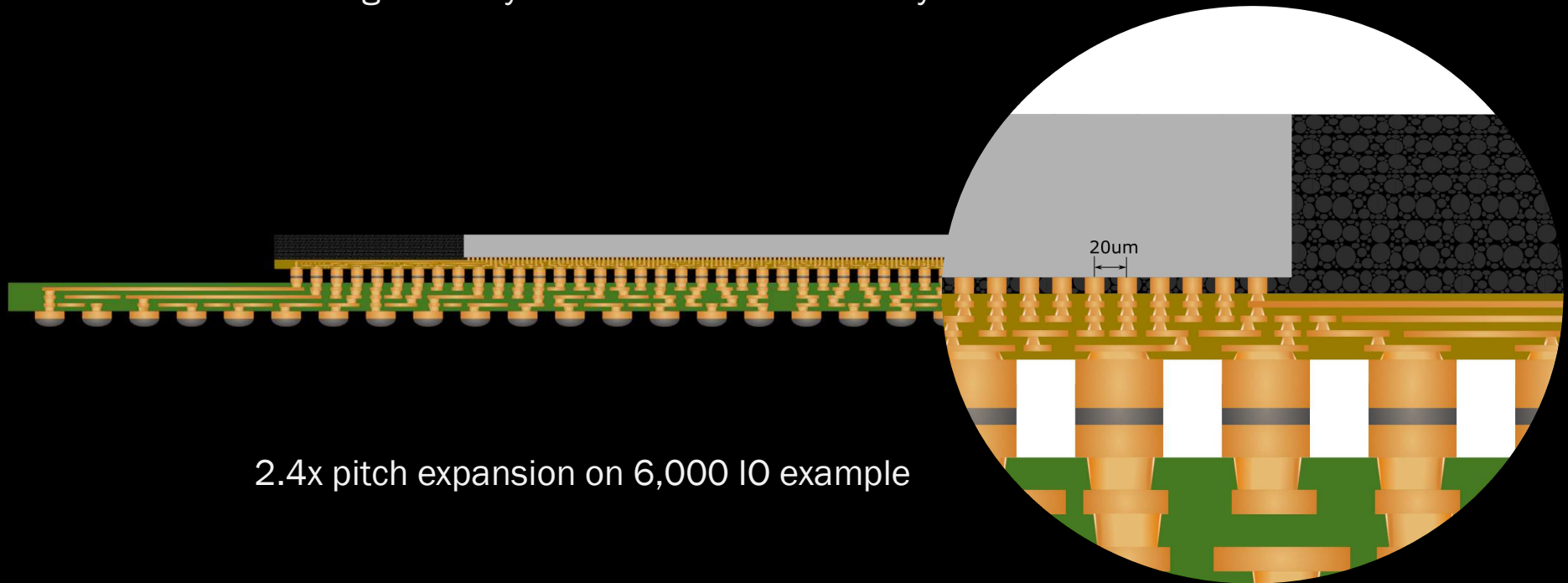
Obstacles - Substrate availability

Significant shortfall in advanced substrate capacity is forecasted to persist



Solution – Simpler Substrates

FOCoS moves high-density interconnect to fan-out layers



2.4x pitch expansion on 6,000 IO example

Obstacle – Shift Happens™

1. Variation in mechanical placement of die

2. Displacement

- Chiplet architectures drive increasing die per package
- Each die placement & subsequent processing adds risk
- One die shifted out of position can lead to failure

Actual die position varies
from designed nominal

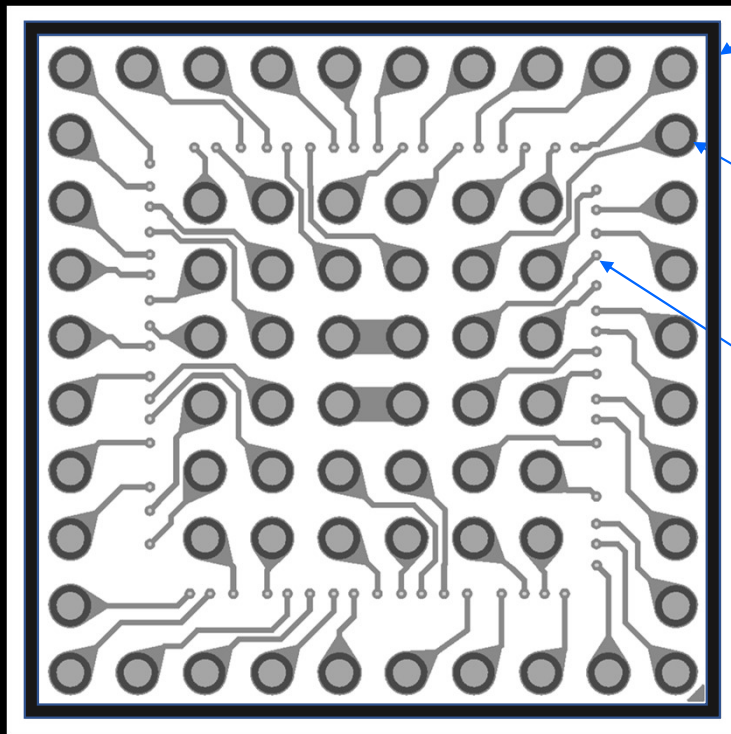
Die placement tolerance
X, Y, & rotation

Mold displacement
(during embedding)

Adaptive Patterning Methods™

Adaptive Alignment

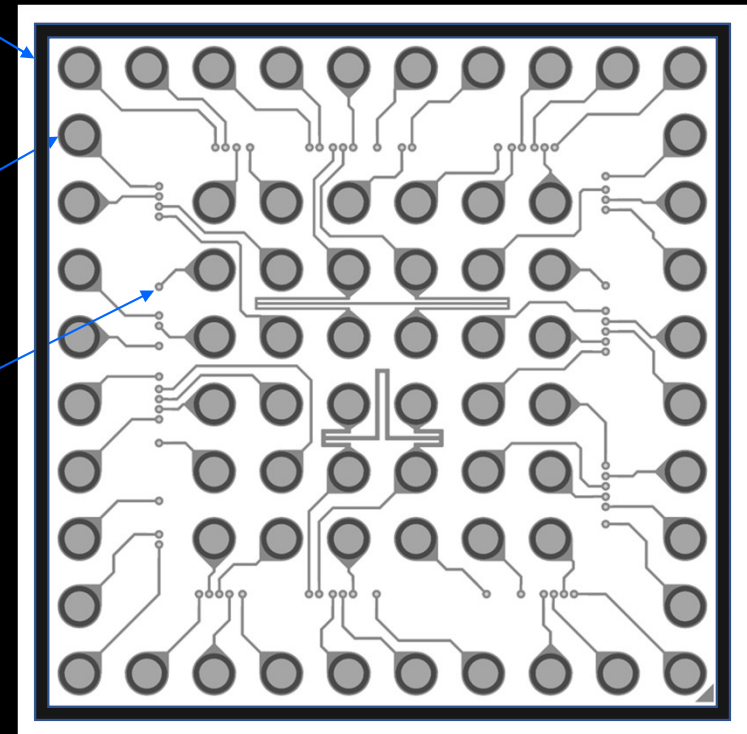
Translate & rotate entire RDL pattern to the measured die position



BGA array fixed to package outline – precise RDL pattern to die alignment

Adaptive Routing

Dynamically adapt small portion of RDL to the measured die position (s)



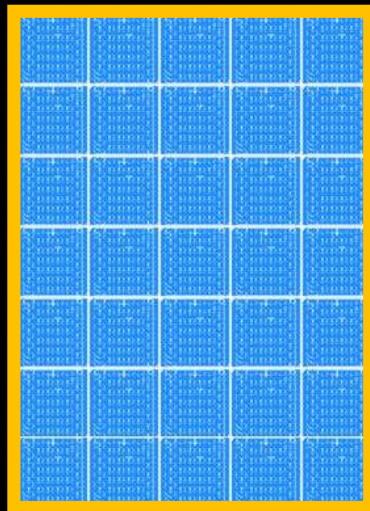
BGA array fixed to package outline – ideal for multi-die routing

Obstacles - Reticle Size

- Reticle limits typically $\sim 850\text{mm}^2$
- Chiplet based devices often $36\text{mm} \times 36\text{mm}$ ($1,296\text{mm}^2$) and larger
- Reticle stitching required – technically feasible, commercially unattractive

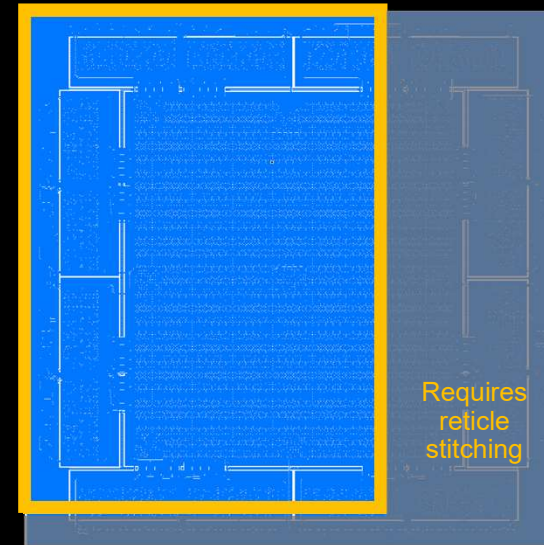
5x5 mm Device

Devices within reticle



36x36 mm Device

Beyond reticle size

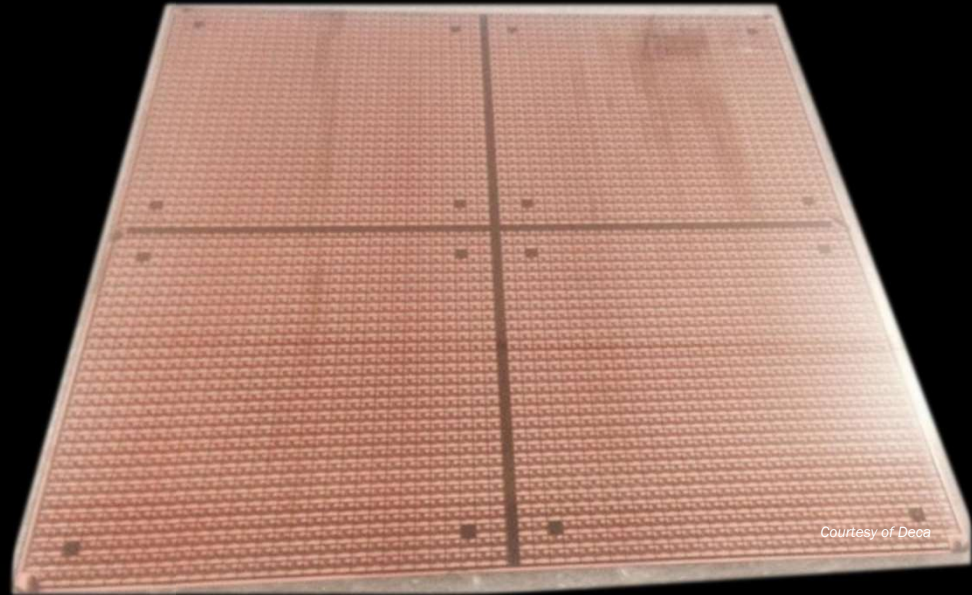


Solution – Eliminate the Reticle



Mask-less LDI lithography system

Large Panel Production



Courtesy of Deca

600mm x 600mm square panel

Adaptive Patterning utilizes fully digital lithography – no glass photomasks are used

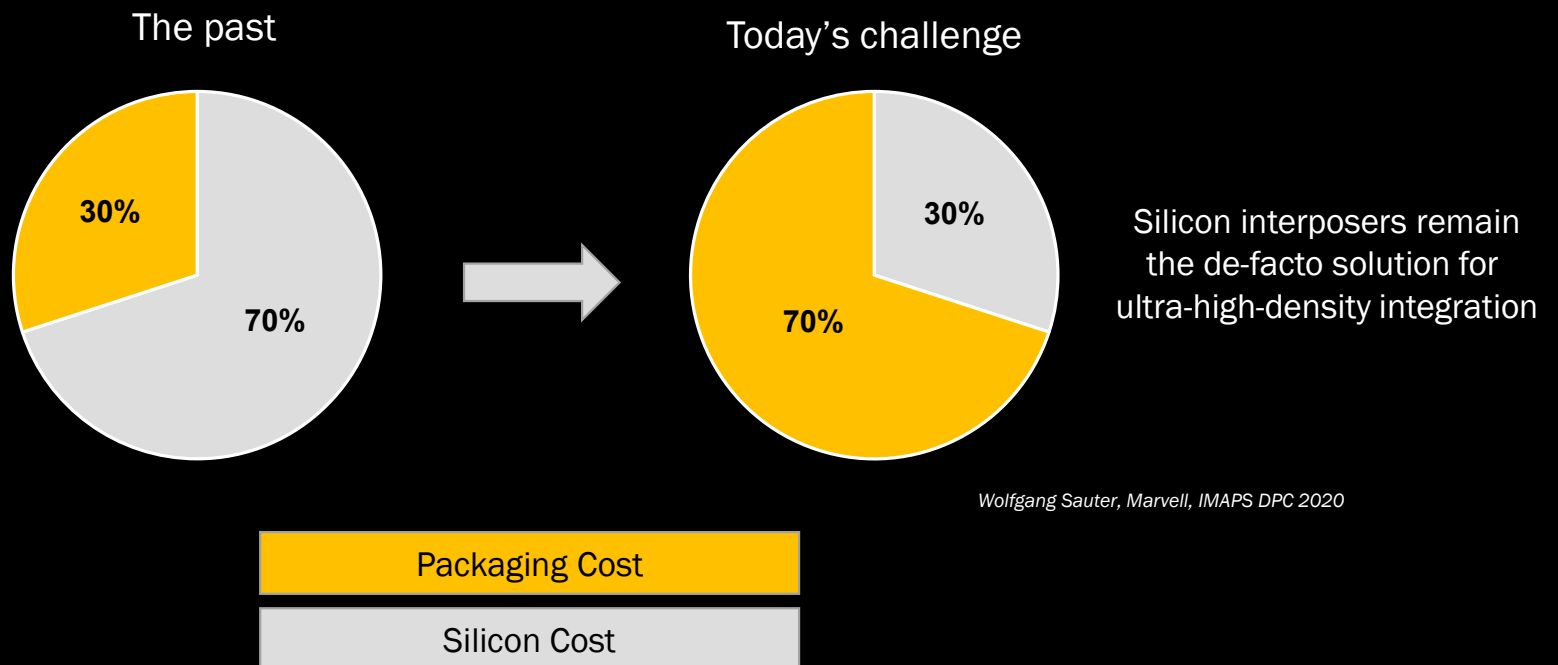
Entire 300mm round or 600mm square panel is a single exposure field



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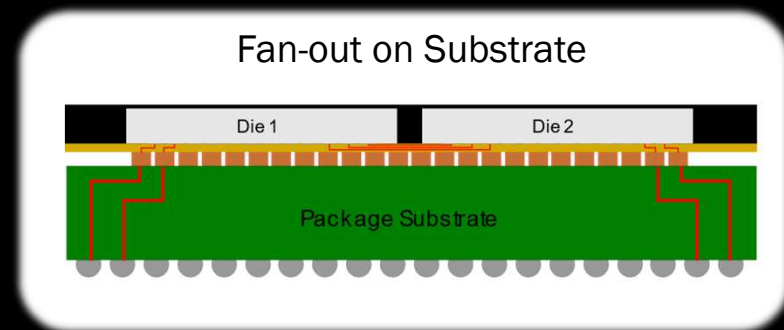
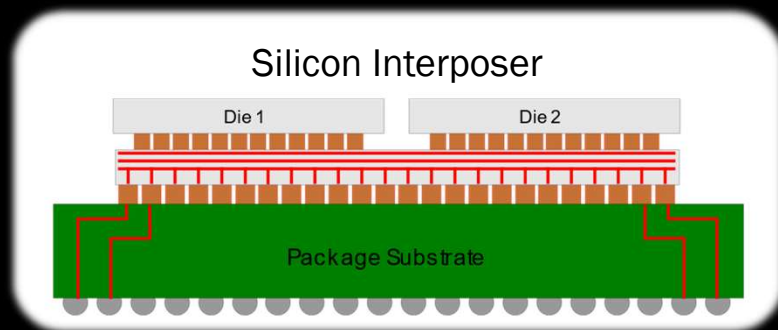
Obstacles - Cost

Next generation packaging technologies demand costly materials and processes



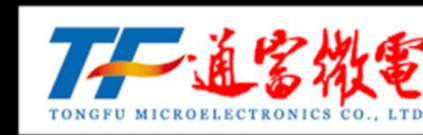
Solution – Eliminate the Si Interposer

Ultra-high-density organic solutions are positioned to replace Si interposers

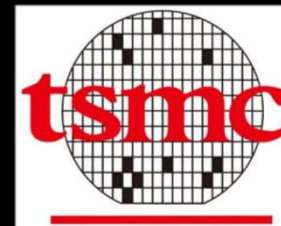


Obstacles – Emerging Proprietary Solutions

Established independent supply chain for semiconductor packaging through the OSATs

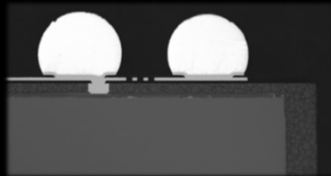


However, latest advanced packaging technologies emerging from proprietary sources



Solution – Independent Advanced Technology

Ready access to advanced packaging technology – Deca's proven solutions



M-Series Fan-out

*Chips first, chips up
fan-out technology*

Gen 1 & Gen 2



Adaptive Patterning*

*Real-time optimized design
during manufacturing (every
device on every wafer)*

Deca's current licensees

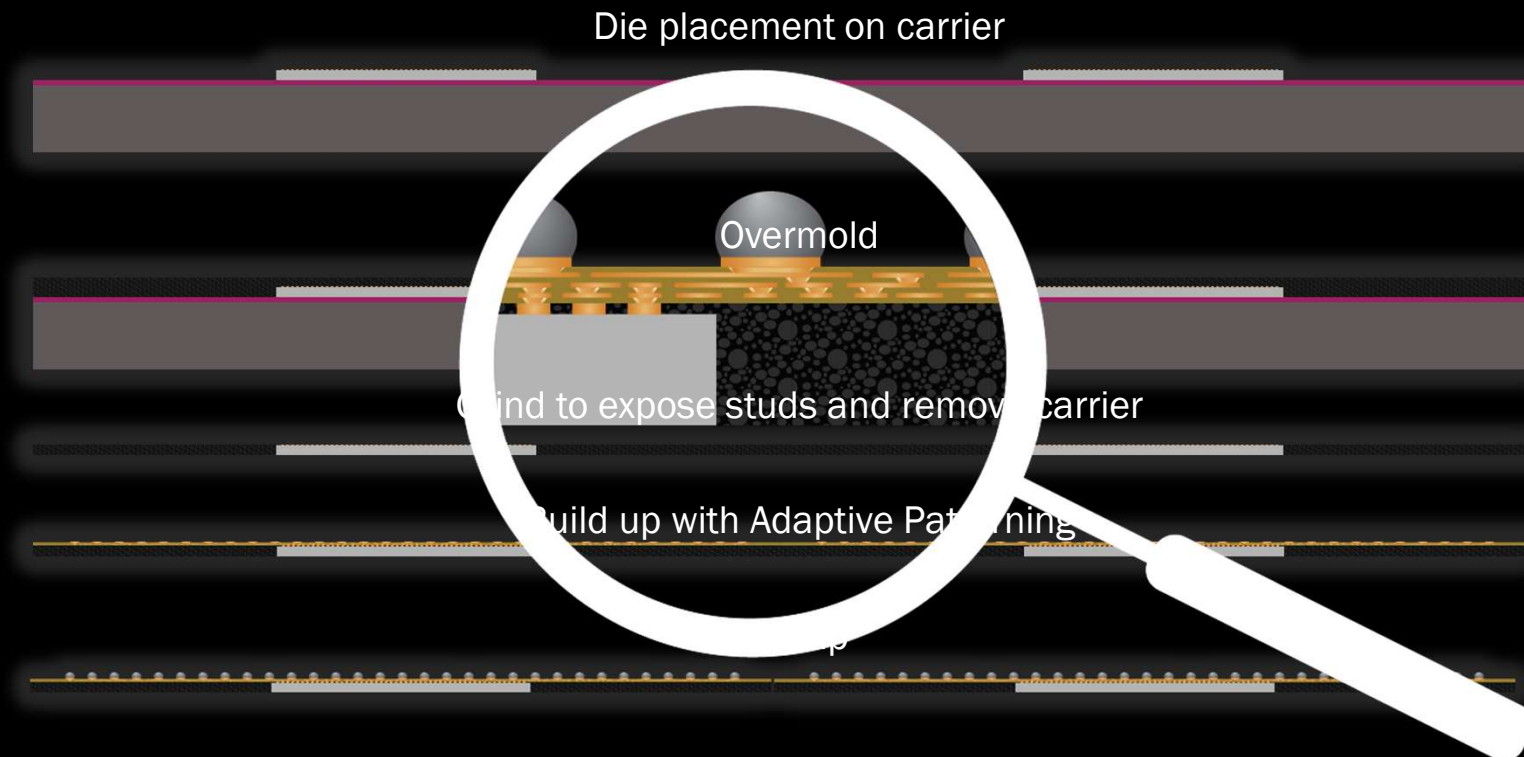


And growing...



Solution – A Simple Process

M-Series chips first face up advanced fan-out technology

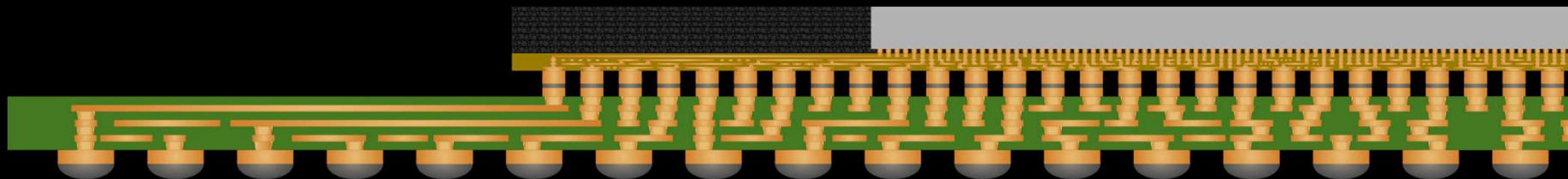


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FOCoS Design Study

FOCoS moves high-density interconnect to fan-out layers



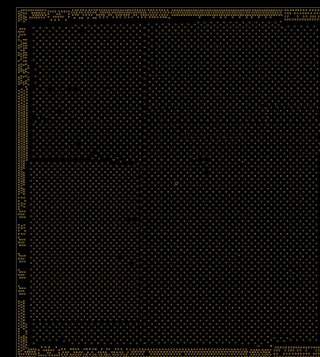
- 14mm x 16mm finished device
- 6,000 die pads with 2.4x expansion

FOCoS Design Study

Die specifications

- 4nm silicon
- 12mm x 13 mm
- 4500 core pins – 150 μm pitch
- 1500 periphery pins – 90 μm pitch

Die



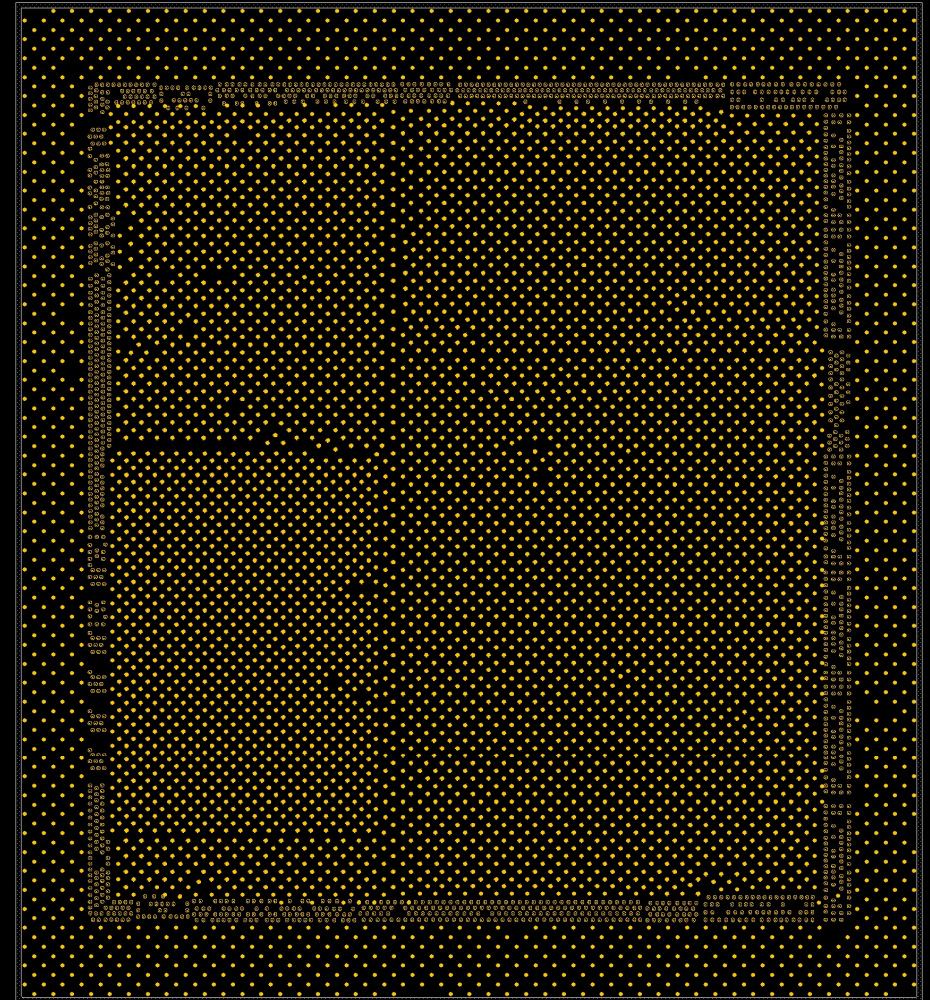
FOCoS Design Study

Molded M-Series Package

- 5 μm minimum trace & space
- 14 x 16 mm
- 1 routing layer
- 4500 core pins – 150 μm pitch
- 1500 periphery pins – 212 μm pitch

FOR = 1.44

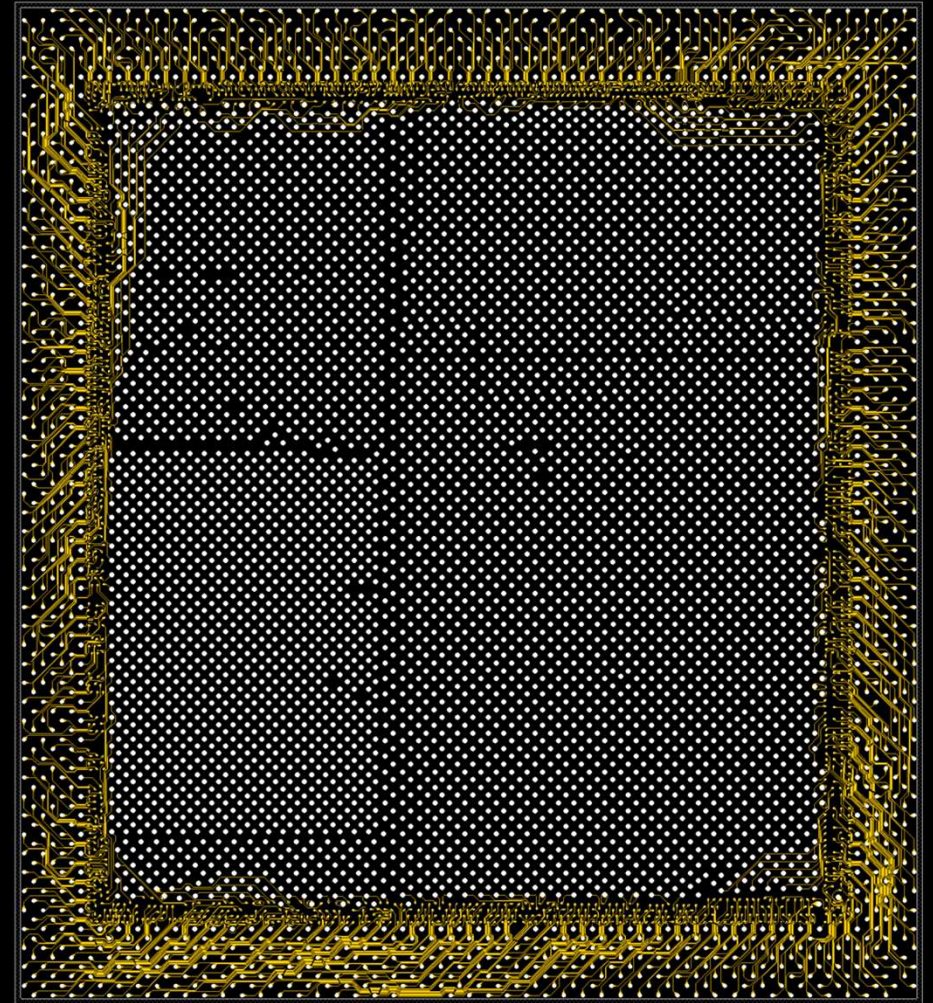
Fan-Out Ratio



FOCoS Design Study

Adding RDL

- Achieved full routing in single layer
- 5 μm minimum trace & space

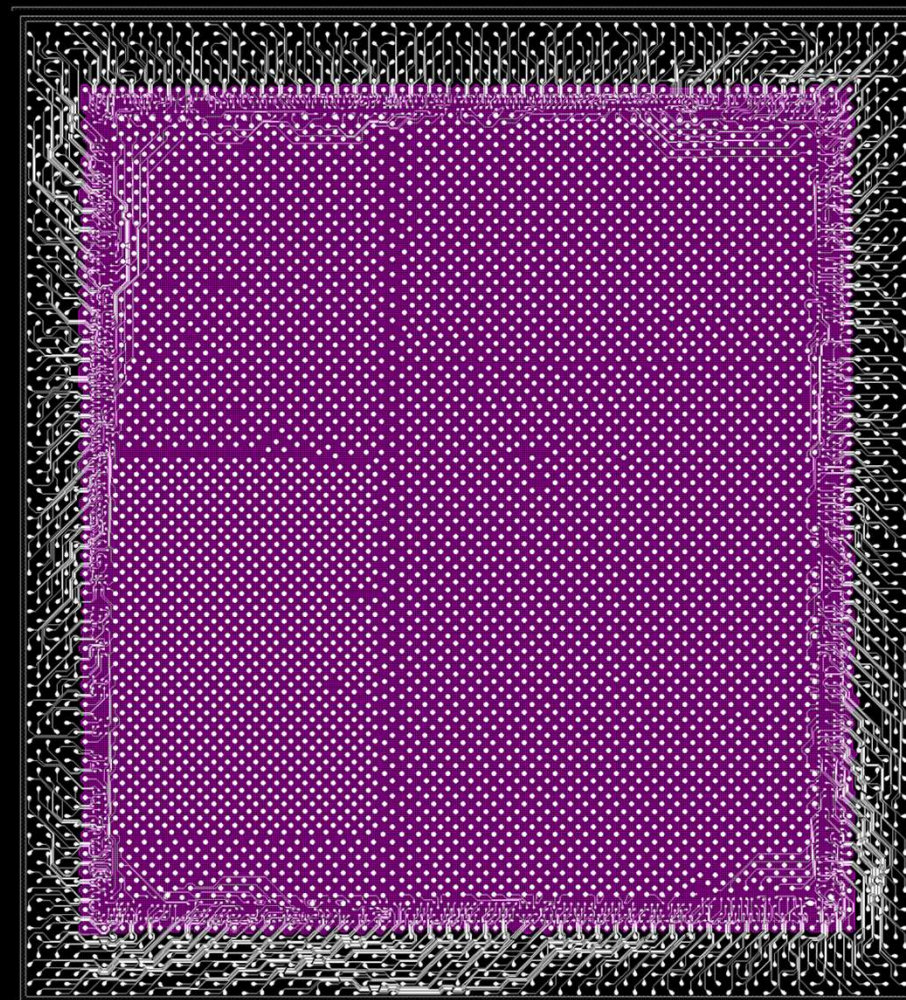


FOCoS Design Study

Adaptive Patterning

Adaptive Alignment

- Translates & rotates pattern precisely to measured die location (vias & RDL)

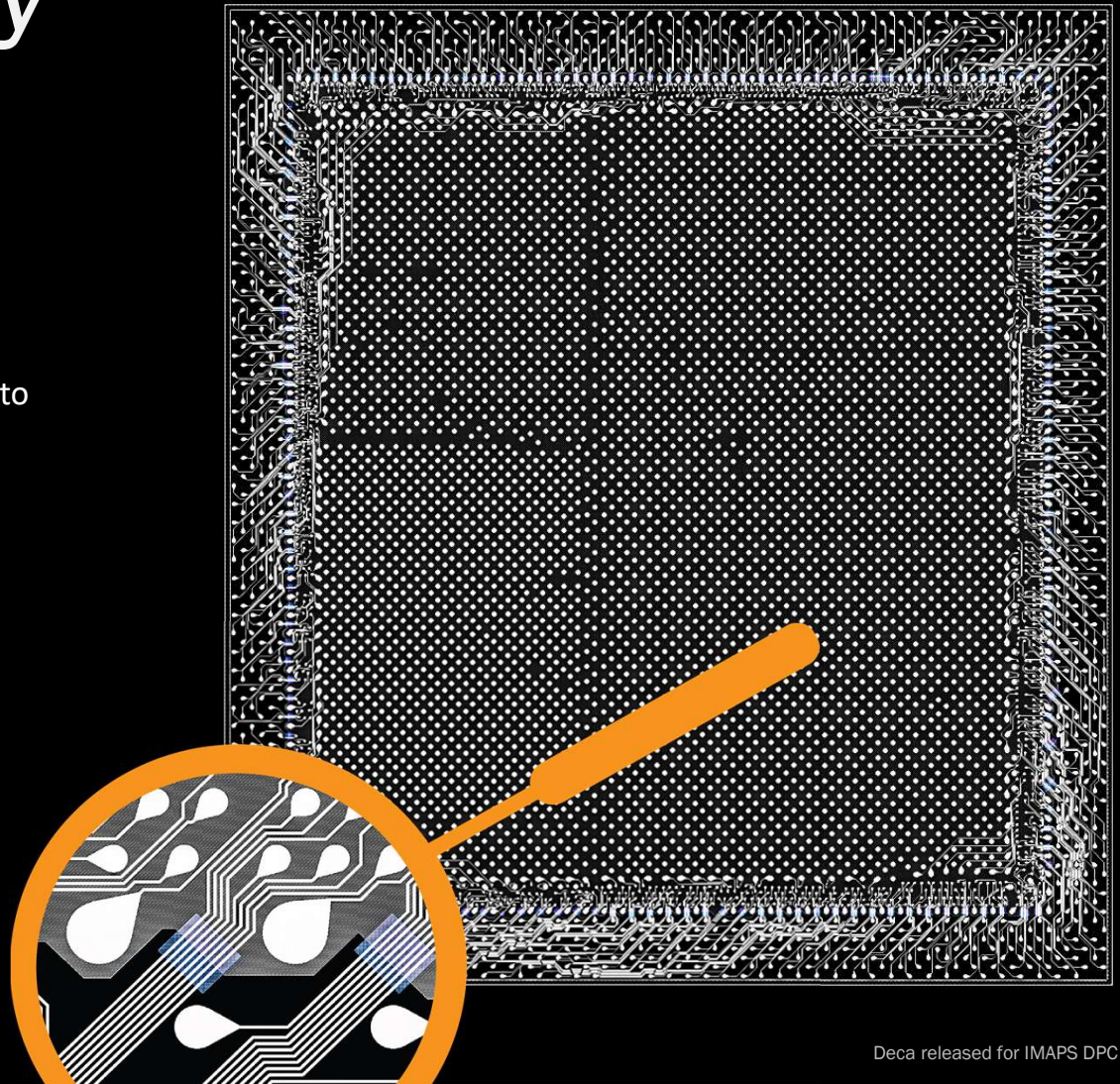


FOCoS Design Study

Adaptive Patterning

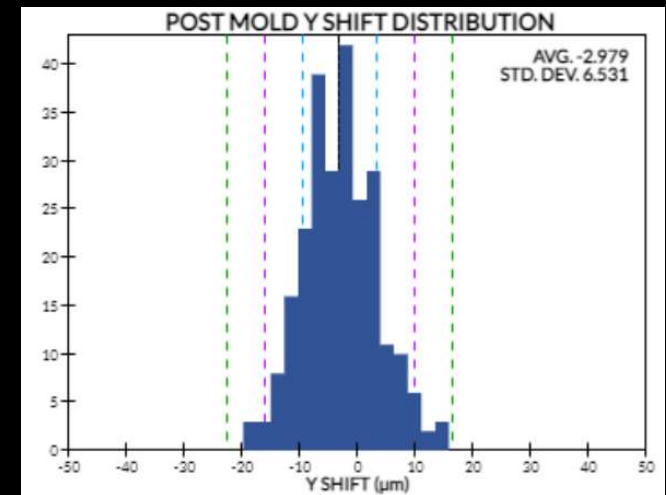
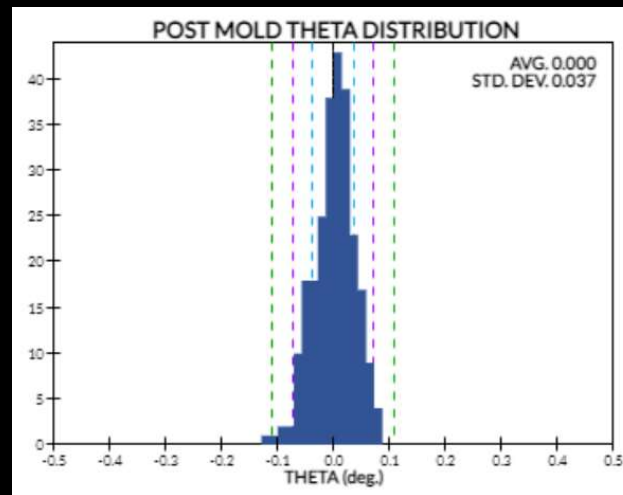
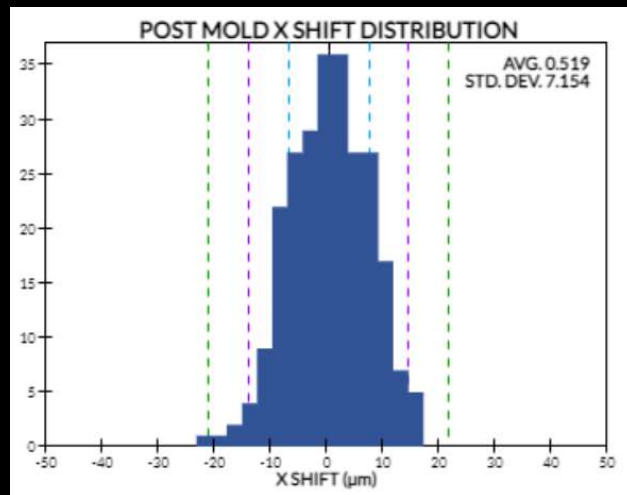
Adaptive Routing

- Dynamically adapt small portion of RDL to precisely complete the connection



FOCoS Design Study

Simulated natural variation of $\pm 20\mu\text{m}$ XY and $\pm 0.1^\circ$ rotation at 3σ (typical production values)

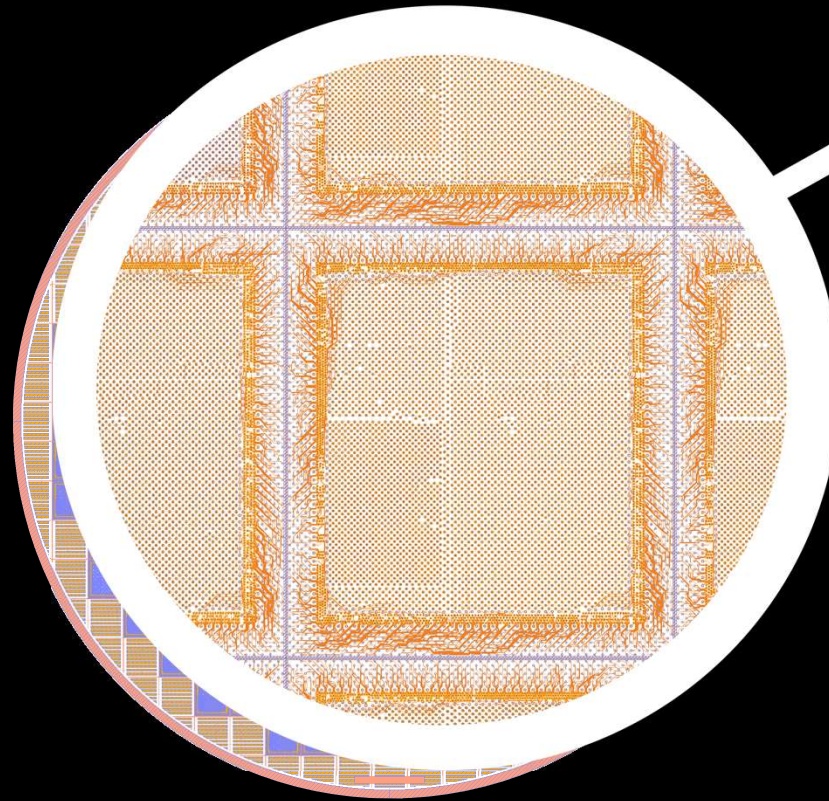


Simulated die displacement histograms

FOCoS Design Study

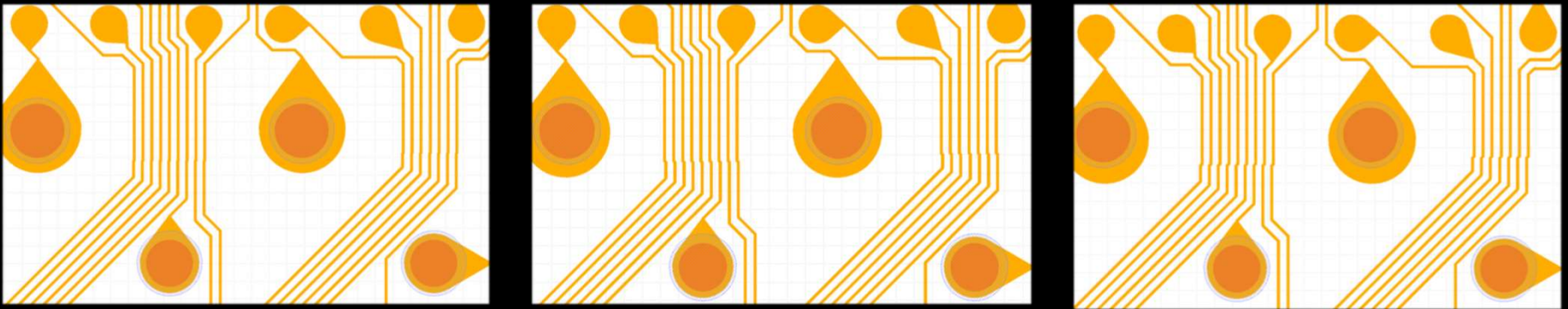
Simulation results

100% yield across
all die shifts



FOCoS Design Study

Physical trace variants across the simulated die shift range

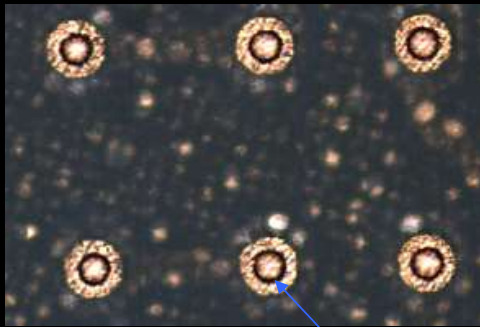


Actual RDL variation is negligible

FOCoS Design Study

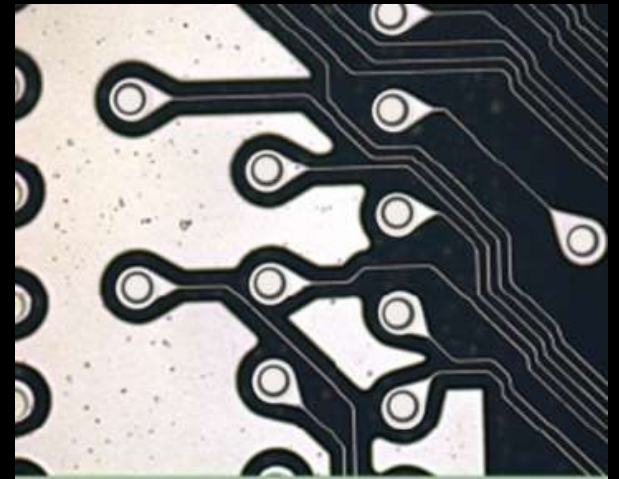
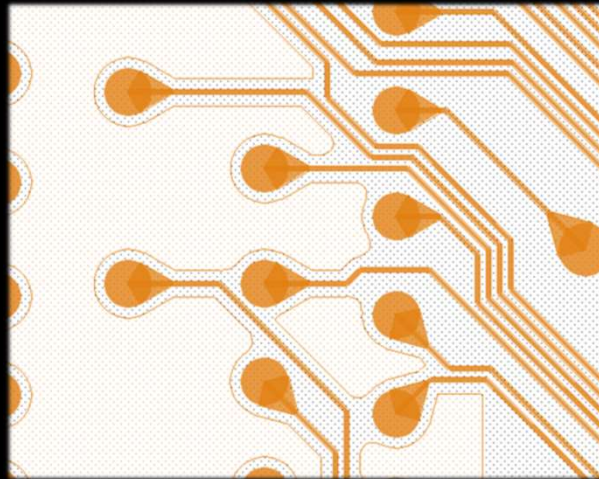
Actual customer device build

Adaptive Alignment



Vias aligned to
Cu stud centers

Adaptive Routing



Conclusion

- Chiplets are now
- Multiple barriers currently exist for mass adoption
- M-Series & Adaptive Patterning provide powerful solutions
- Proven capability through actual FOCoS customer designs

The technology is ready



Thank you from  **DECA**



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